

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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		Examiner	Art Unit	Page 1 of 1
		Steve Nguyen	2138	

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**NON-PATENT DOCUMENTS**

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	U	IEEE Standard Test Access Port and Boundary-Scan Architecture; IEEE Std1149.1-1990.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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